



Advanced Characterization of Functional Materials

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Message from the Guest Editors

The fundamental understanding of the origin of functional properties of materials at the microscopic level and the development of comprehensive models to predict these properties are fields of intense research. The essential properties of these materials may be remarkably altered by the size, topology, shape of their constituent phases and surface topography, resulting in entirely different optical, mechanical, electrical, and magnetic properties.

This Special Issue covers advanced characterization techniques, including all methods of microscopy (light, 2 photons, electron, etc.), analysis (microanalysis and surface analytical techniques), and spectroscopic characterization (Raman, LIBS, laser, etc.), with topics connecting the preparation and the resulting relevant functional properties.

It is our pleasure to invite you to submit a manuscript to this Special Issue. Full papers, short communications, and reviews would be greatly appreciated.





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Message from the Editor-in-Chief

As the world of science becomes ever more specialized, researchers may lose themselves in the deep forest of the ever increasing number of subfields being created. This open access journal Applied Sciences has been started to link these subfields, so researchers can cut through the forest and see the surrounding, or quite distant fields and subfields to help develop his/her own research even further with the aid of this multi-dimensional network.

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